

"RESPONSE UNDER 37 CFR 1.116-EXPEDITED PROCEDURE EXAMINING

GROUP 2/28

OBLON SPIVAK **McClelland** MAIER NEUSTADT P.C.

ATTORNEYS AT LAW

**COMMISSIONER FOR PATENTS** ALEXANDRIA, VIRGINIA 22313

RE: Application Serial No.: 10/028,319

Applicants: Sanae ITO, et al. Filing Date: December 28, 2001

For: SIMULATION METHOD, SIMULATION

Docket No.: 217804US2

PROGRAM, AND SEMICONDUCTOR DEVICE MANUFACTURING METHOD EACH EMPLOYING

**BOUNDARY CONDITIONS** 

Group Art Unit: 2128

Examiner: Gebresilassie, K.K.

SIR:

Attached hereto for filing are the following papers:

## REQUEST FOR RECONSIDERATION UNDER 37 CFR §1/116

Our check in the amount of \$0.00 attached covering any required fees. In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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DOCKET NO: 217804US2

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

SANAE ITO, ET AL. : EXAMINER: GEBRESILASSIE, K.K.

SERIAL NO: 10/028,319

FILED: DECEMBER 28, 2001 : GROUP ART UNIT: 2128

FOR: SIMULATION METHOD, SIMULATION PROGRAM, AND SEMICONDUCTOR DEVICE MANUFACTURING METHOD EACH EMPLOYING BOUNDARY CONDITIONS

## REQUEST FOR RECONSIDERATION UNDER 37 CFR §1.116

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated November 28, 2005, please amend the aboveidentified application as follows:

Remarks/Arguments begin on page 2 of this paper.